

L Number	Hits	Search Text	DB	Time stamp
1	3603	calibrat\$4 with probe	USPAT	2002/11/07 13:12
2	652	((calibrat\$4 with probe) with system	USPAT	2002/11/07 13:13
3	96	((calibrat\$4 with probe) with system) and wafer	USPAT	2002/11/07 13:13
6	16876	"96" and (refer\$6 near3 point)	USPAT	2002/11/07 13:52
7	27	((calibrat\$4 with probe) with system) and wafer) and (refer\$6 near3 point)	USPAT	2002/11/07 14:43
8	1744	calibrat\$4 near5 contact	USPAT	2002/11/07 14:52
9	264	(calibrat\$4 near5 contact) and (wafer or semiconductor)	USPAT	2002/11/07 14:52
10	106	((calibrat\$4 near5 contact) and (wafer or semiconductor)) and probe	USPAT	2002/11/07 14:53
-	246	calibrat\$4 near5 test\$4 near5 (wafer or substrate)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/11/06 16:44
-	219837	contact and conductor	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/11/06 16:45
-	54	(calibrat\$4 near5 test\$4 near5 (wafer or substrate)) and (contact and conductor)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2002/11/06 16:46
-	10	(calibrat\$4 near5 test\$4 near5 (wafer or substrate)) and 324/72.5, 601,130,202.ccls.	USPAT	2002/11/06 17:21
-	2	"6300757"	USPAT	2002/11/06 17:21
-	7	("5734268" "5748506" "5866437" "5884236" "5910011" "5929628" "6032107").PN.	USPAT	2002/11/06 17:36
-	1	6300757.URPN.	USPAT	2002/11/06 17:37
-	776	calibrat\$4 same (contact same pair)	USPAT	2002/11/06 18:14
-	162	(calibrat\$4 same (contact same pair)) and (wafer or substrate or semiconductor)	USPAT	2002/11/06 17:50
-	6540	calibrat\$4 same (wafer or substrate or semiconductor)	USPAT	2002/11/06 18:14
-	230	(calibrat\$4 same (wafer or substrate or semiconductor)) and (contact with pair)	USPAT	2002/11/06 18:17
-	56	(calibrat\$4 same (wafer or substrate or semiconductor)) and ((contact with pair) with (semiconductor or wafer or substrate))	USPAT	2002/11/06 18:28
-	71	(calibrat\$4 same (wafer or substrate or semiconductor)) and ((contact or pad) with pair) with (semiconductor or wafer or substrate))	USPAT	2002/11/06 18:28